

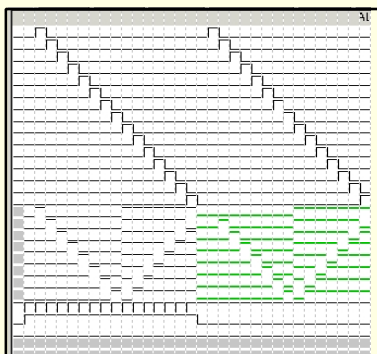
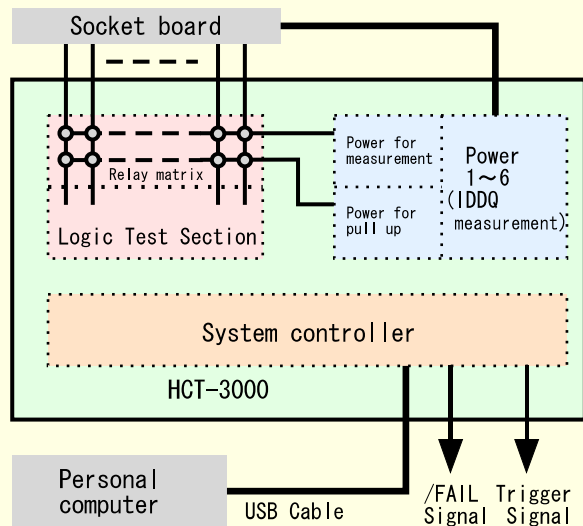
# Ultra Compact LSI Tester

## HCT-3000 series

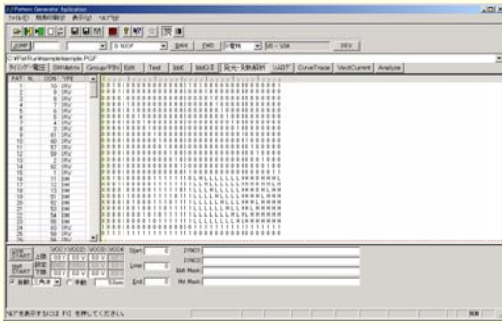
Carrying is possible because it is very small.

### Features

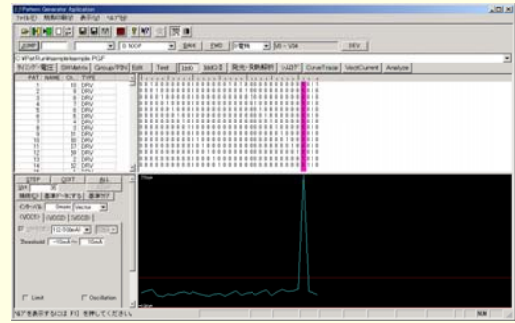
- ◆ **Iddq Measurement**  
Each Vector Address Iddq Measurement
- ◆ **Logic and Function test**
- ◆ **Each pin Full Controllable**
- ◆ **All pin Open-Short Measurement**
- ◆ **For EMMI/OBIRCH/EB Tester**
- ◆ **Possible to compile the pattern Data of general LSI tester.**



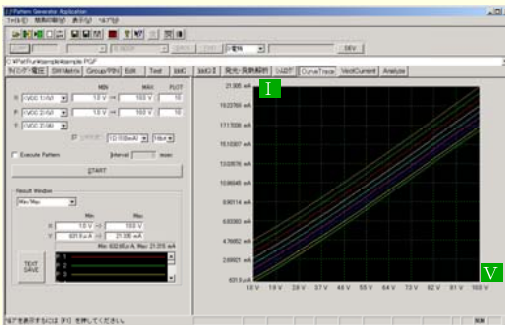
## EMMI Test Screen



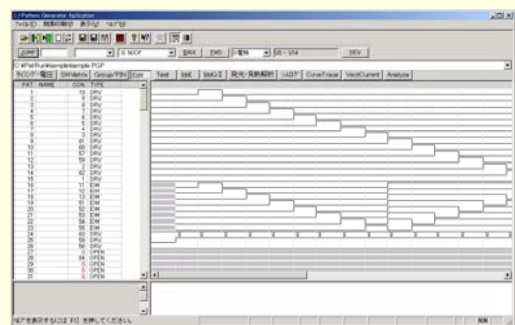
## Iddq Measure Screen



## Electric Parameter measure Screen



## Pattern Edit Screen



## Specification

Count pins	256pins, 512pins
Test rate setting	100ns~1.3ms
Width setting	20ns~1.3ms
Delay setting	20ns~1.3ms
I/O switch timing	256
Strobe setting	80ns~1.3ms ※
AD Strobe setting	80ns~1.3ms (rate 100μ~1.3ms) ※
Split rate(Timing Block)	8level
Pattern data memory	512kW
Fail log memory	256
Drive Level	Vih1=2V~5V, Vih2=1V~2.5V, Vil=0V (More than 3V, cannot use above timing sets) ※
Comparator Level	Vo=0V~5V (The value that is more than set value is High, the others is Low.)
Vcc	-5V~+10V (Vdd) (1mA-1A Limit set) (More than 3V, output current is less than 1A) ※
Idd Measure Range	1, 100m, 10m, 1m, 100uA, 10μA
Supply Current Range(I Force)	1, 100m, 10m, 1m, 100uA, 10μA
Dimension	W=330mm, D=310mm, H=200mm
Weight	5kg

※Please refer to detailed document.

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● Agency

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